

2023 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT 2023)

**Juan-Les-Pins, France
3-5 October 2023**



**IEEE Catalog Number: CFP23078-POD
ISBN: 979-8-3503-1501-1**

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IEEE Catalog Number:	CFP23078-POD
ISBN (Print-On-Demand):	979-8-3503-1501-1
ISBN (Online):	979-8-3503-1500-4
ISSN:	2576-1501

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